

TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (L²-π-MOSV)

2SJ511

Chopper Regulator, DC-DC Converter and Motor Drive Applications

- 4 V gate drive
- Low drain-source ON resistance : $R_{DS(ON)} = 0.32 \Omega$ (typ.)
- High forward transfer admittance : $|Y_{fs}| = 1.4 S$ (typ.)
- Low leakage current : $I_{DSS} = -100 \mu A$ (max) ($V_{DS} = -30 V$)
- Enhancement-mode : $V_{th} = -0.8 \sim -2.0 V$ ($V_{DS} = -10 V, I_D = -1 mA$)

Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Drain-source voltage	V_{DSS}	-30	V
Drain-gate voltage ($R_{GS} = 20 k\Omega$)	V_{DGR}	-30	V
Gate-source voltage	V_{GSS}	± 20	V
Drain current	DC (Note 1)	I_D	-2 A
	Pulse (Note 1)	I_{DP}	-6 A
Drain power dissipation	P_D	0.5	W
Drain power dissipation (Note 2)	P_D	1.5	W
Single pulse avalanche energy (Note 3)	E_{AS}	55	mJ
Avalanche current	I_{AR}	-2	A
Repetitive avalanche energy (Note 4)	E_{AR}	0.05	mJ
Channel temperature	T_{ch}	150	°C
Storage temperature range	T_{stg}	-55~150	°C

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	$R_{th(ch-a)}$	250	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: Mounted on ceramic substrate (25.4 mm × 25.4 mm × 0.8 mm)

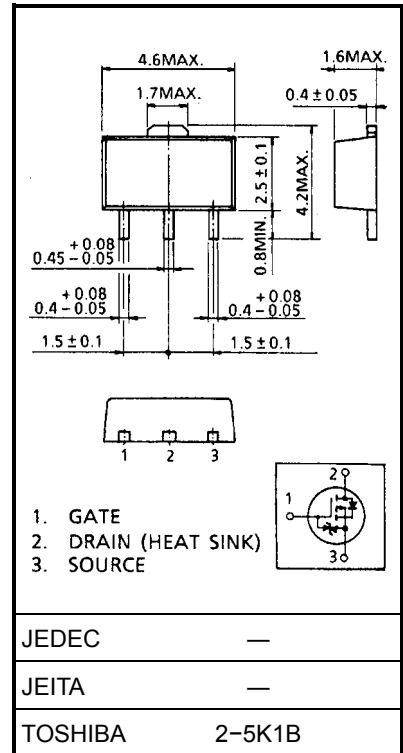
Note 3: $V_{DD} = -25 V, T_{ch} = 25^\circ C$ (initial), $L = 10 mH, R_G = 25 \Omega, I_{AR} = -2 A$

Note 4: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device.

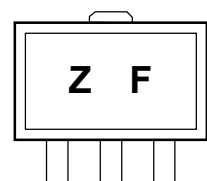
Please handle with caution.

Unit: mm



Weight: 0.05 g (typ.)

Marking



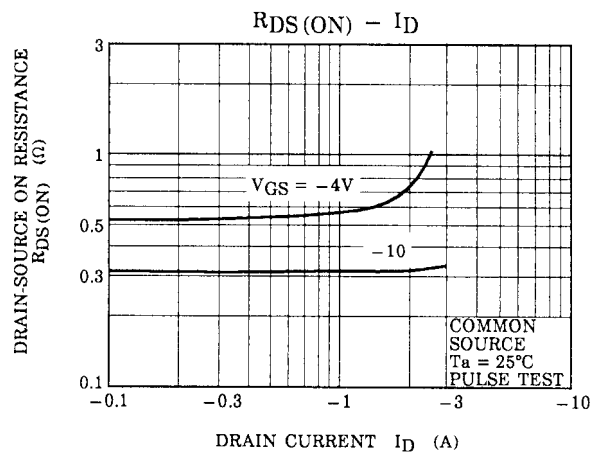
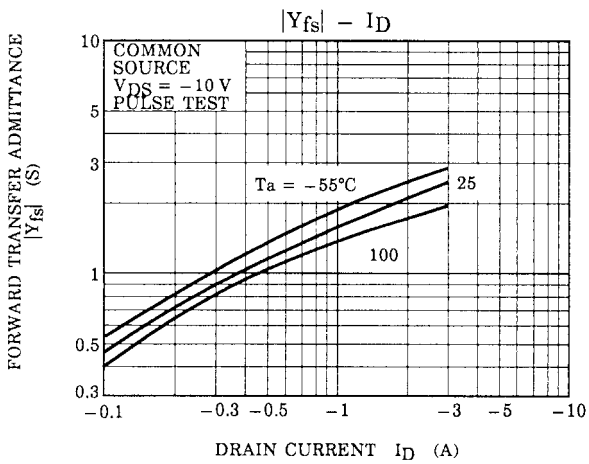
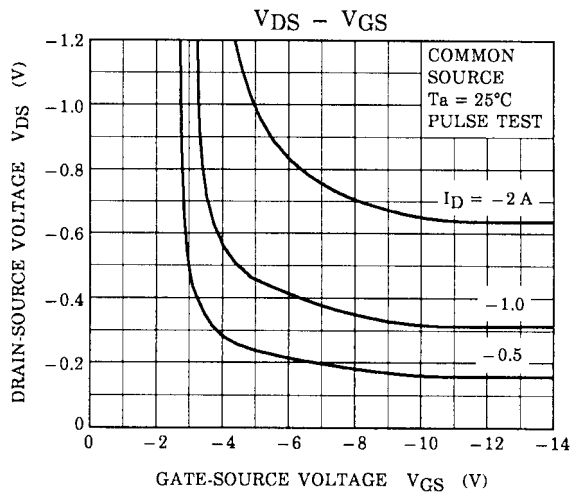
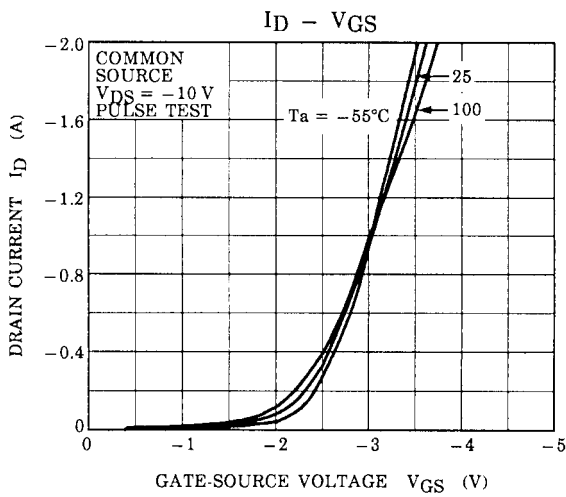
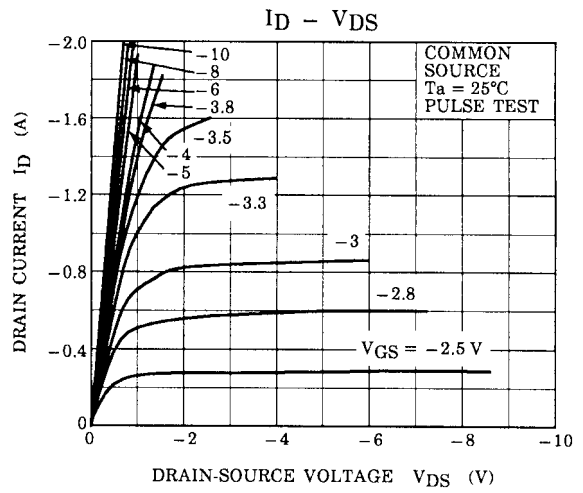
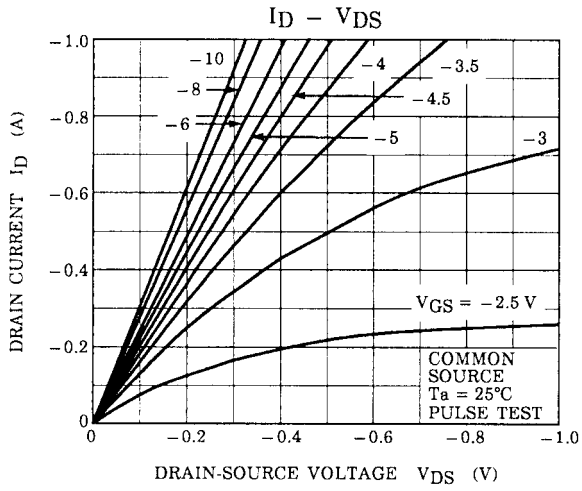
(The two digits represent the part number.)

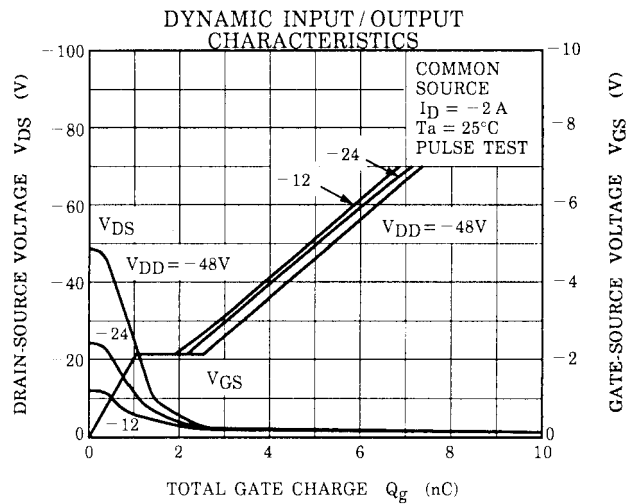
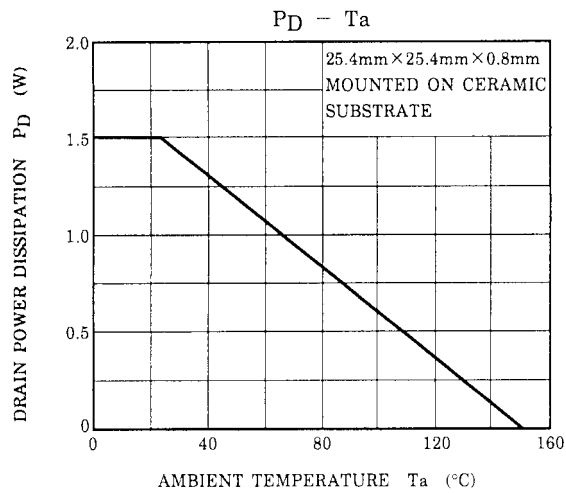
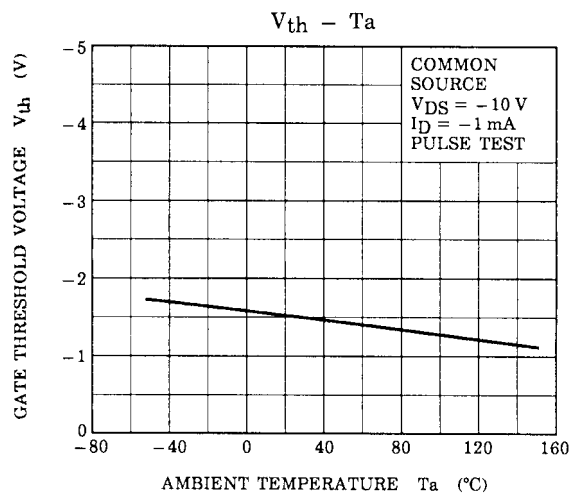
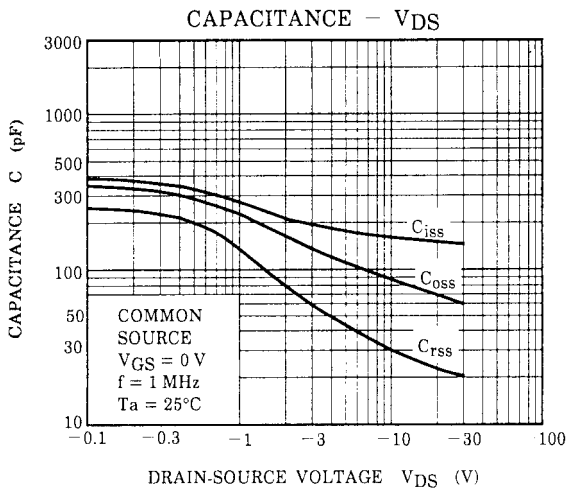
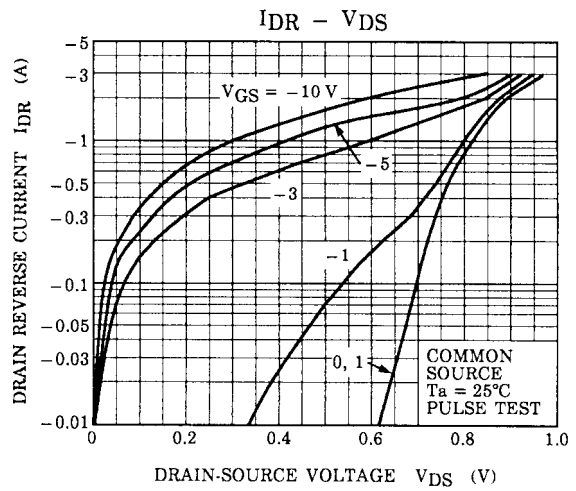
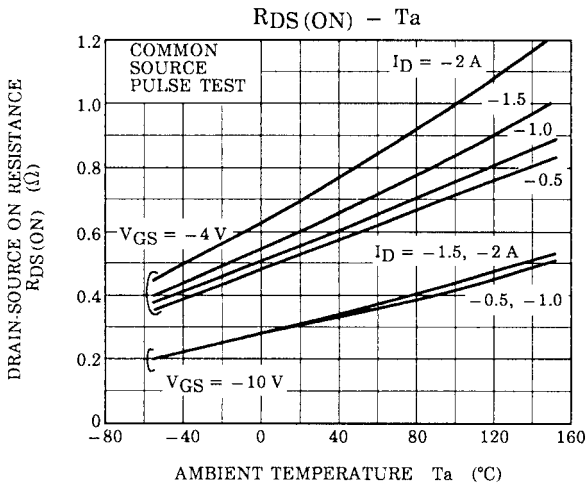
Electrical Characteristics (Ta = 25°C)

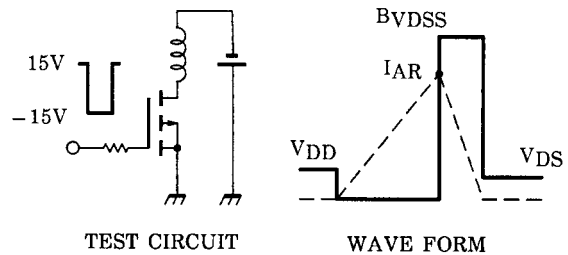
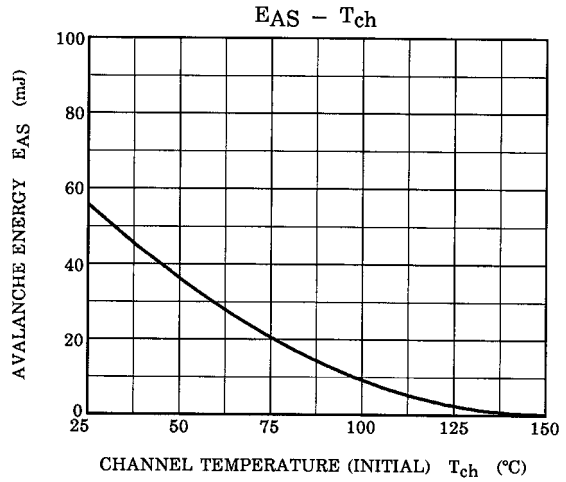
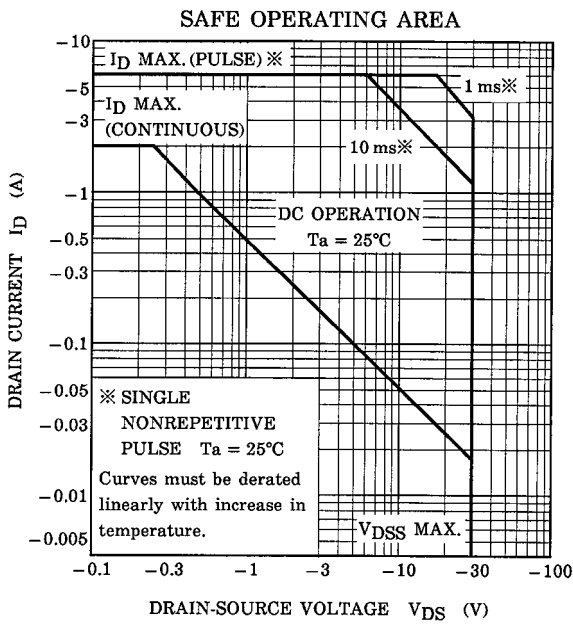
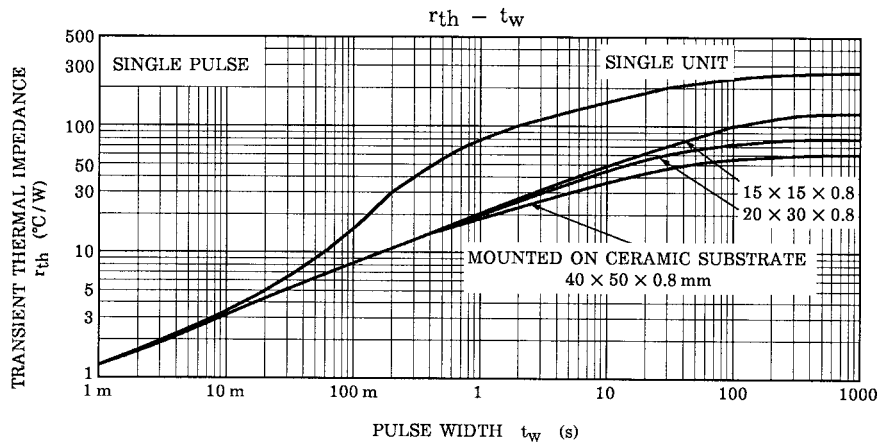
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	$V_{GS} = \pm 16\text{ V}, V_{DS} = 0\text{ V}$	—	—	± 10	μA
Drain cut-off current		I_{DSS}	$V_{DS} = -30\text{ V}, V_{GS} = 0\text{ V}$	—	—	-100	μA
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = -10\text{ mA}, V_{GS} = 0\text{ V}$	-30	—	—	V
Gate threshold voltage		V_{th}	$V_{DS} = -10\text{ V}, I_D = -1\text{ mA}$	-0.8	—	-2.0	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = -4\text{ V}, I_D = -1\text{ A}$	—	0.55	0.76	Ω
			$V_{GS} = -10\text{ V}, I_D = -1\text{ A}$	—	0.32	0.45	
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = -10\text{ V}, I_D = -1\text{ A}$	0.7	1.4	—	S
Input capacitance		C_{iss}	$V_{DS} = -10\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$	—	160	—	pF
Reverse transfer capacitance		C_{rss}		—	30	—	
Output capacitance		C_{oss}		—	85	—	
Switching time	Rise time	t_r	<p>$V_{GS} = -10\text{ V}$ 0 V $50\ \Omega$ $I_D = -1\text{ A}$ V_{OUT} $R_L = 15\ \Omega$ $V_{DD} = -15\text{ V}$ Duty $\leq 1\%$, $t_w = 10\ \mu\text{s}$</p>	—	30	—	ns
	Turn-on time	t_{on}		—	45	—	
	Fall time	t_f		—	30	—	
	Turn-off time	t_{off}		—	120	—	
Total gate charge (Gate-source plus gate-drain)		Q_g	$V_{DD} \approx -24\text{ V}, V_{GS} = -10\text{ V}, I_D = -2\text{ A}$	—	5.5	—	nC
Gate-source charge		Q_{gs}		—	4.3	—	
Gate-drain ("miller") charge		Q_{gd}		—	1.2	—	

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR} (Note 1)	—	—	—	-2	A
Pulse drain reverse current (Note 1)	I_{DRP} (Note 1)	—	—	—	-6	A
Forward voltage (diode)	V_{DSF}	$I_{DR} = -2\text{ A}, V_{GS} = 0\text{ V}$	—	—	1.5	V
Reverse recovery time	t_{rr}	$I_{DR} = -2\text{ A}, V_{GS} = 0\text{ V}$	—	40	—	ns
Reverse recovery charge	Q_{rr}	$dI_{DR} / dt = 50\text{ A} / \mu\text{s}$	—	18	—	nC







$R_G = 25\Omega$
 $V_{DD} = -25V, L = 10mH$

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BV_{DSS}}{BV_{DSS} - V_{DD}} \right)$$

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